

REMARKS

Claims 1-23 are pending. Claims 1, 9 and 17 are amended herein. No new matter has been added as a result of the claim amendments.

Drawings

Replacement figures in compliance with 37 § CFR 1.121(d) are enclosed.

Abstract

The abstract is amended substantially in the manner suggested in the instant Office Action.

Specification

The specification is amended as suggested in the instant Office Action.

35 U.S.C. §102 Rejections

The instant Office Action states that Claims 1-23 are rejected under 35 U.S.C. § 102(e) as being anticipated by Wohl et al. ("Wohl;" U.S. Patent No. 6,950,974). The Applicants have reviewed the cited reference and respectfully submit that the present invention recited in Claims 1-23 is not anticipated by Wohl.

As understood by the Applicants, Wohl only appears to describe the generation of a single seed for multiple test patterns encompassing a list of testable faults. In contrast, the present claimed invention pertains to the selection of one test pattern versus another based on the test results of, for example, a preceding test.

In other words, if in general device testing could be described as a two step process, in which the first step pertains to generating test patterns and the second step pertains to selecting and using one of the test patterns generated in the first step, then Applicants respectfully submit that Wohl pertains only to the first step, while the present claimed invention pertains to the second step.

Furthermore, Applicants respectfully submit that Wohl does not show or suggest selecting a test pattern for a second test based on a diagnosis of test results from a first test.

Specifically, Applicants respectfully submit that Wohl does not show or suggest “sending a first test pattern to a device under test (DUT), … wherein a first test is executed using said first test pattern; evaluating test results for said first test and received from said DUT …; automatically selecting a second test pattern … based on a diagnosis of said anomalous data by said test apparatus; and sending said second test pattern to said DUT, wherein a second test is executed using said second test pattern” as recited in independent Claim 1 and as similarly recited in independent Claims 9 and 17.

Even more specifically, Applicants respectfully submit that Wohl does not show or suggest “recognizing a pattern in said anomalous data, wherein said second test pattern is selected according to said pattern” as recited in Claim 8 and as similarly recited in Claims 16 and 23. While Wohl appears to describe generating test patterns to test certain faults, Applicants respectfully submit that

Wohl does not show or suggest selecting a test pattern based on the specific nature of the results of a preceding test.

In summary, Applicants respectfully submit that Wohl does not show or suggest the present claimed invention as recited in independent Claims 1, 9 and 17. Accordingly, Applicants respectfully submit that the basis for rejecting Claims 1, 9 and 17 under 35 U.S.C. § 102(e) is traversed and that these claims are in condition for allowance.

Claims 2-8, 10-16 and 18-23 depend from Claim 1, 9 or 17 and recite additional limitations. Therefore, Applicants also respectfully submit that the basis for rejecting Claims 2-8, 10-16 and 18-23 under 35 U.S.C. § 102(e) is traversed and that these claims are in condition for allowance.

Conclusions

In light of the above remarks, Applicants respectfully request reconsideration of the rejected claims.

Based on the arguments presented above, Applicants respectfully assert that Claims 1-23 overcome the rejections of record and, therefore, Applicants respectfully solicit allowance of these claims.

Applicants have reviewed the reference cited but not relied upon and did not find this reference to show or suggest the present claimed invention: U.S. Patent No. 5,646,948.

The Examiner is invited to contact Applicants' undersigned representative if the Examiner believes such action would expedite resolution of the present Application.

Respectfully submitted,

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